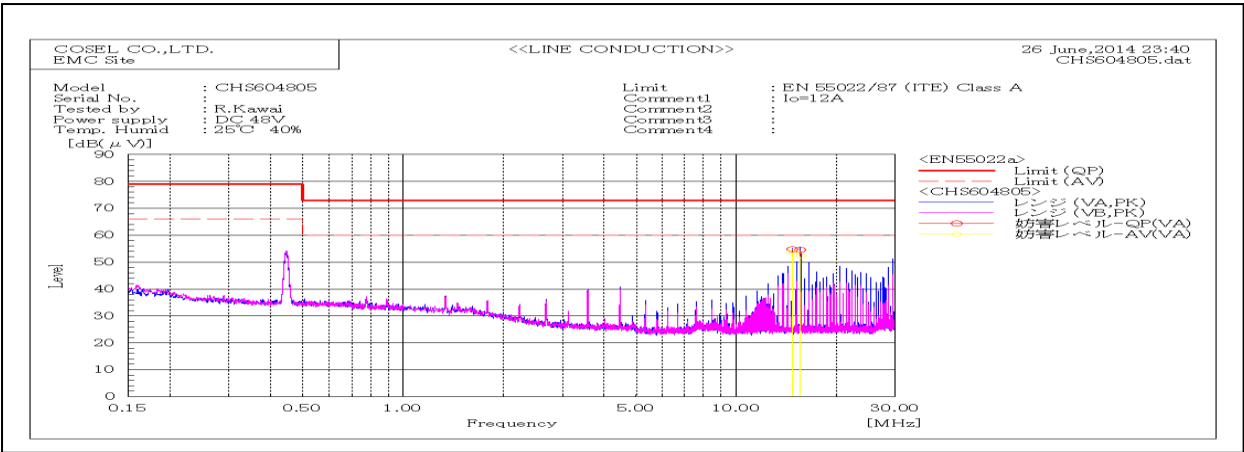
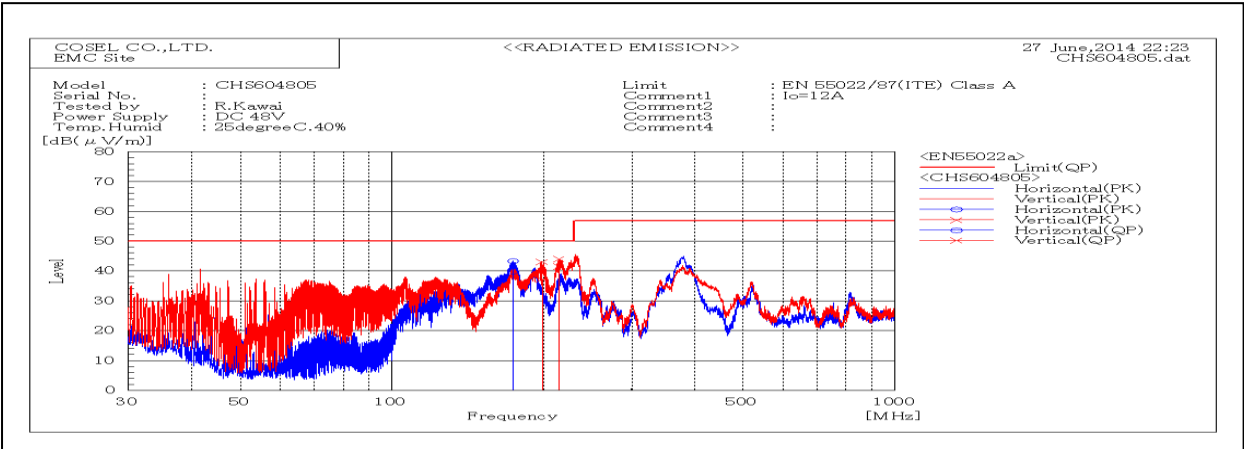


DATA SHEET		Date	26-Sep-14
Model	CHS604805	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



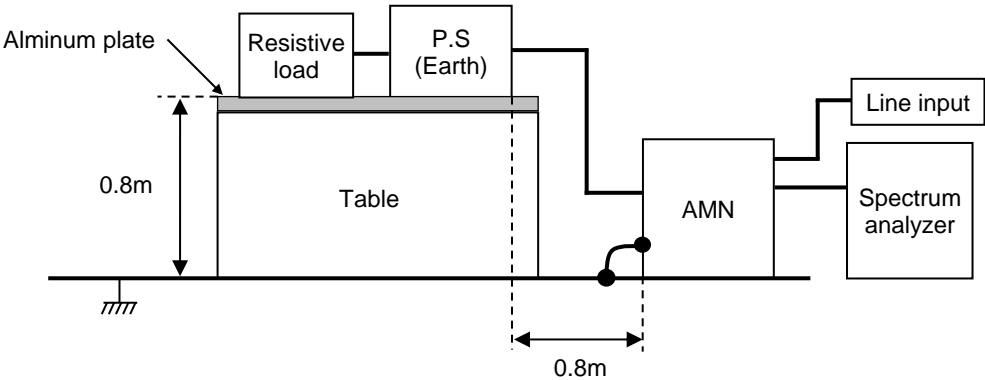
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
14.74905		VA	33.9	32.9	20.8	54.7	53.7	73	60	18.3	6.3	Pass	
15.63365		VA	33.7	31.4	20.9	54.6	52.3	73	60	18.4	7.7	Pass	



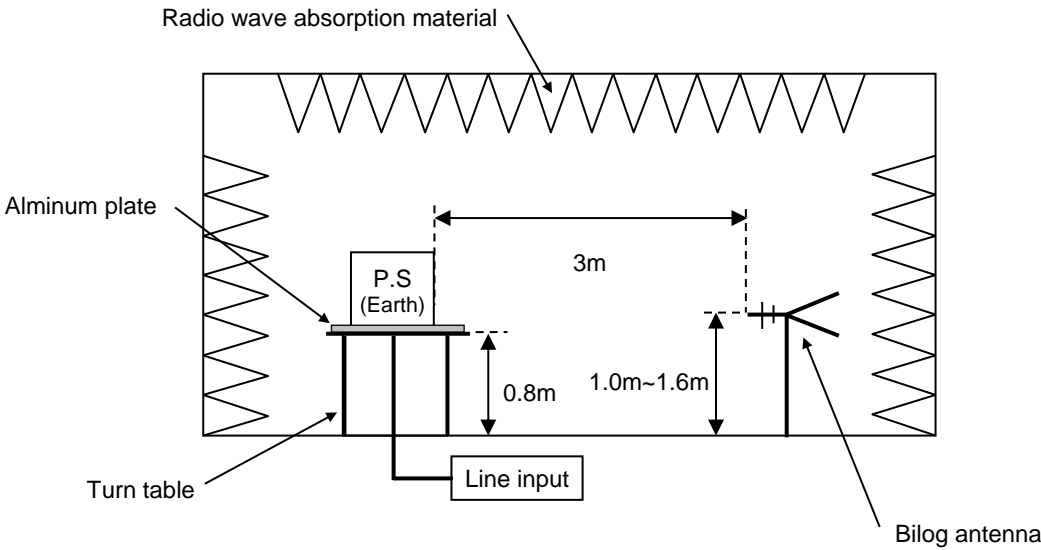
Frequency MHz	Harm	Polarization	Stability	Reading	Space Loss dB	Level	Limit	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
				dB(μV) QP		dB(m W) QP	dB(m W) QP					
174.169		H	Stable	61.9	-22.1	39.8	50	10.2	Pass	136	92	
198.686		V	Stable	52.8	-15.7	37.1	50	12.9	Pass	103	292	
214.386		V	Stable	56.4	-15	41.4	50	8.6	Pass	102	295	

DATA SHEET		Date	26-Sep-14
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

1. Line conduction



2. Radiated emission



Conditions

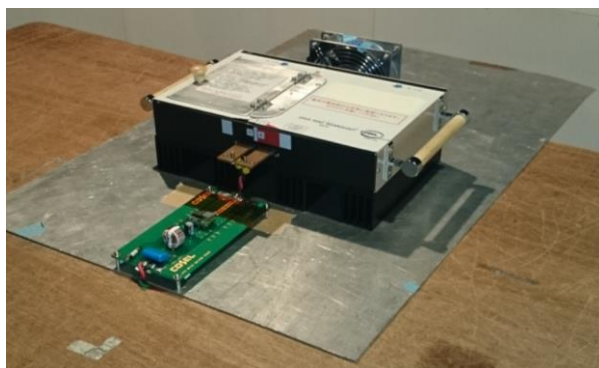
Test : EMI
Model Name : CHS60

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

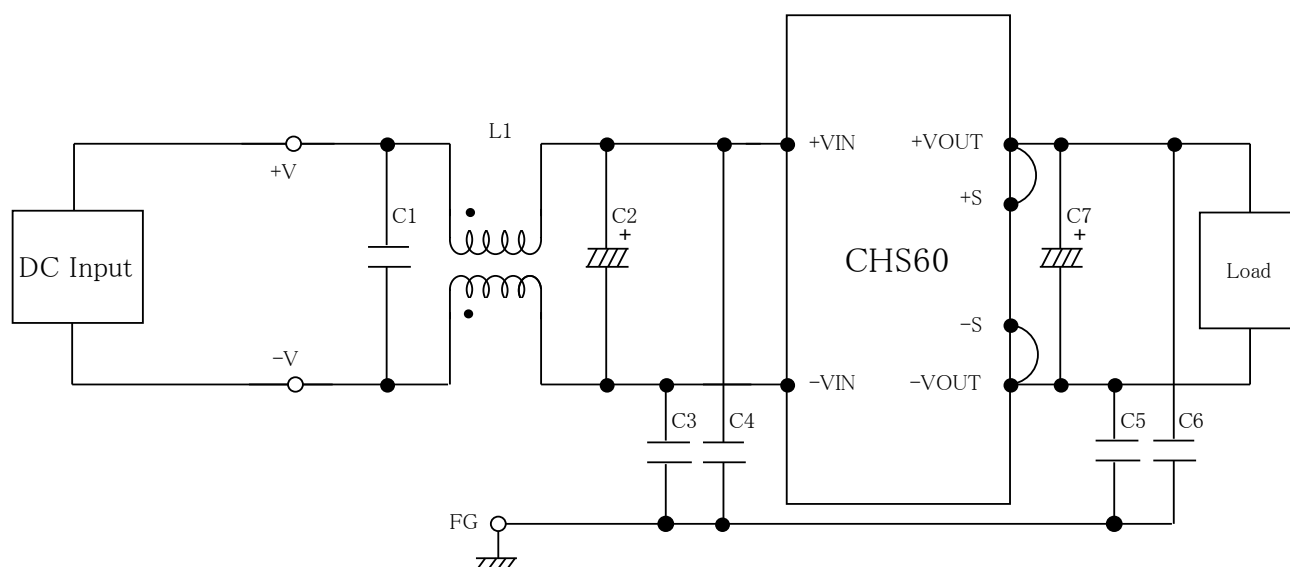


Fig.1 Testing circuitry

L1 : 1mH SC-05-10J (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C7 : 100V 68 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)
C7 : 50V 10 μ F PMseries (nichicon)